

Notic of References Cited	Application/Control No. 09/943,667		Applicant(s)/Patent Under Reexamination KIKUCHI ET AL.	
	Examiner Toniae M. Thomas		Art Unit 2822	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,932,897 B1	08-1999	KAWAGUCHI et al.	257/141
	B	US-5,981,997 B1	11-1999	KITAMURA	257/355
	C	US-6,198,131 B1	03-2001	TUNG	257/345
	D	US-6,307,224 B1	10-2001	SHIRAI	257/288
	E	US-6,392,274 B1	05-2002	TUNG	257/339
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Wolf Ph.D., Stanley, "Hot-Carrier-Resistant Processing and Device Structure," Silicon Processing for the VLSI Era - Vol. 3: The Submicron MOSFET, Lattice Press, 1995, pages 588-590.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.